

20V N-Channel Enhancement Mode MOSFET

Description

The AP30N02BF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

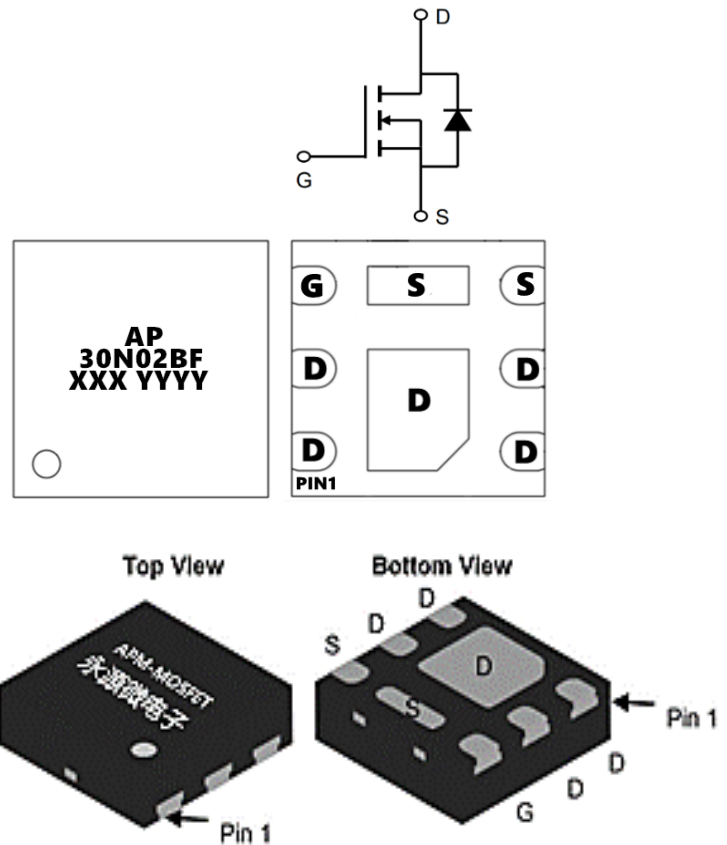
General Features

$V_{DS} = 20V$ $I_D = 30A$

$R_{DS(ON)} < 8.5m\Omega @ V_{GS}=4.5V$ (Type: 7.8m Ω)

Application

solar road lights
Load switch
Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30N02BF	QFN2*2-6L	AP30N02BF XXX YYYY	3000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_C=25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	30	A
$I_D @ T_C=100^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	19	A
I_{DM}	Pulsed Drain Current ²	90	A
E_{AS}	Single Pulse Avalanche Energy ³	30	mJ
$P_D @ T_C=25^{\circ}C$	Total Power Dissipation ⁴	20.8	W
$P_D @ T_A=25^{\circ}C$	Total Power Dissipation ⁴	2	W
T_{STG}	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹	125	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	6	$^{\circ}C/W$

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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$I_D = 250\text{mA}$, $V_{GS}=0\text{V}$	20	-	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}$, $V_{GS}=0\text{V}$	-	-	1.0	mA
IGSS	Gate-Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 12\text{V}$	-	-	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\text{mA}$	0.5	0.75	1.0	V
RDS(ON)	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS}=4.5\text{V}$, $I_D=6\text{A}$	-	7.8	8.5	m Ω
		$V_{GS}=2.5\text{V}$, $I_D=3\text{A}$	-	10	13	m Ω
Ciss	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=10\text{V}$, $f = 1\text{MHz}$	-	1195	-	pF
Coss	Output Capacitance		-	175	-	pF
Crss	Reverse Transfer Capacitance		-	150	-	pF
Qg	Total Gate Charge	$V_{GS}=0$ to 4.5V $V_{DD}=10\text{V}$, $I_D=15\text{A}$	-	13	-	nC
Qgs	Gate Source Charge		-	2.5	-	nC
Qgd	Gate Drain("Miller") Charge		-	3.5	-	nC
td(on)	Turn-On DelayTime	$V_{GS} = 4.5\text{V}$, $V_{DD}=10\text{V}$ $I_D= 15\text{A}$, $R_{GEN}=3\Omega$	-	8	-	ns
tr	Turn-On Rise Time		-	19	-	ns
td(off)	Turn-Off DelayTime		-	30	-	ns
tf	Turn-Off Fall Time		-	11	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	30	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	120	A
VSD	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_S=30\text{A}$	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F=15\text{A}$, $di/dt=100\text{A/us}$	-	7.5	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	1.5	-	nC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3、The power dissipation is limited by 150°C junction temperature
- 4、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

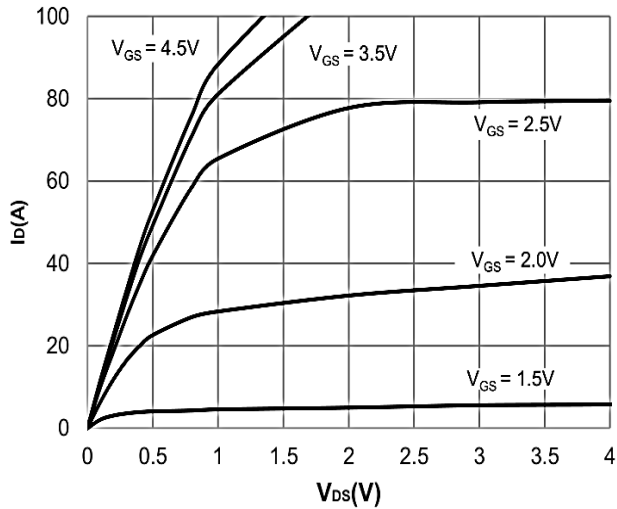


Figure 1: Output Characteristics

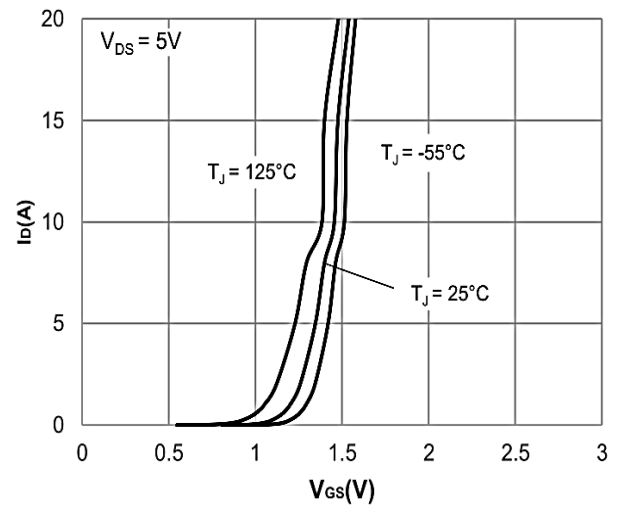


Figure 2: Typical Transfer Characteristics

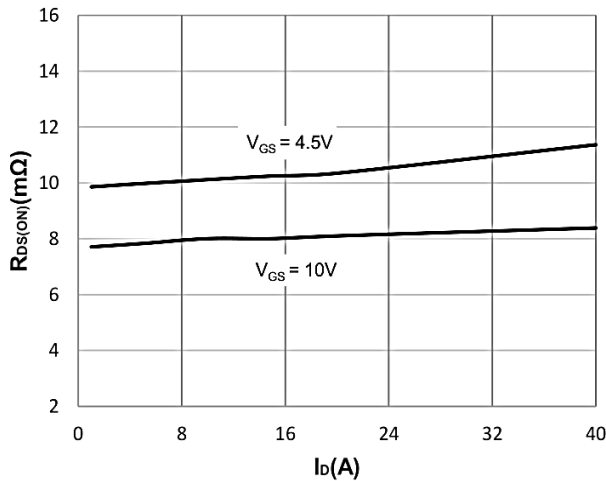


Figure 3: On-resistance vs. Drain Current

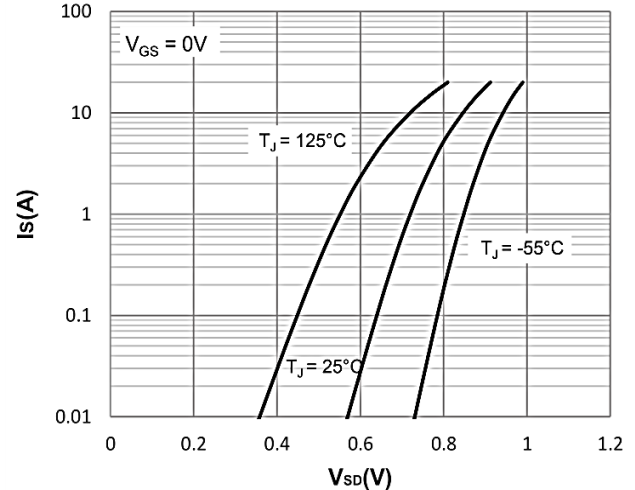


Figure 4: Body Diode Characteristics

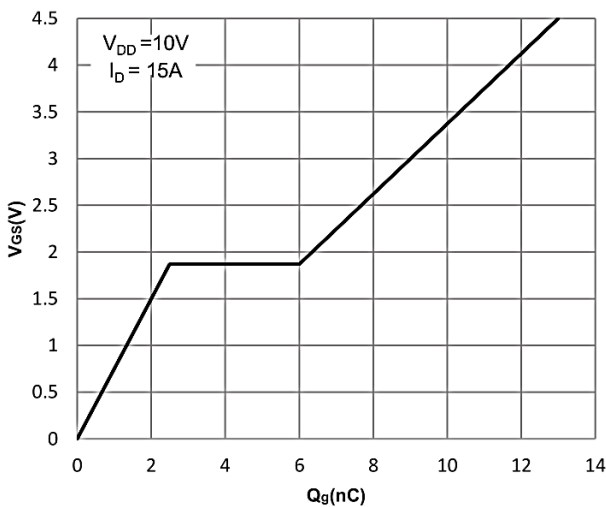


Figure 5: Gate Charge Characteristics

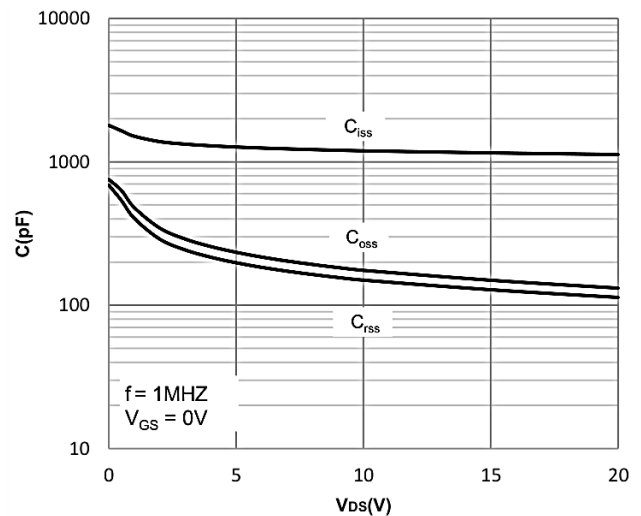


Figure 6: Capacitance Characteristics

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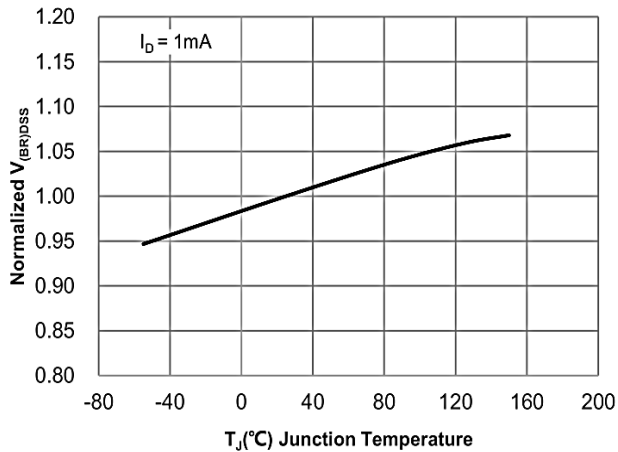


Figure 7: Normalized Breakdown voltage vs. Junction Temperature

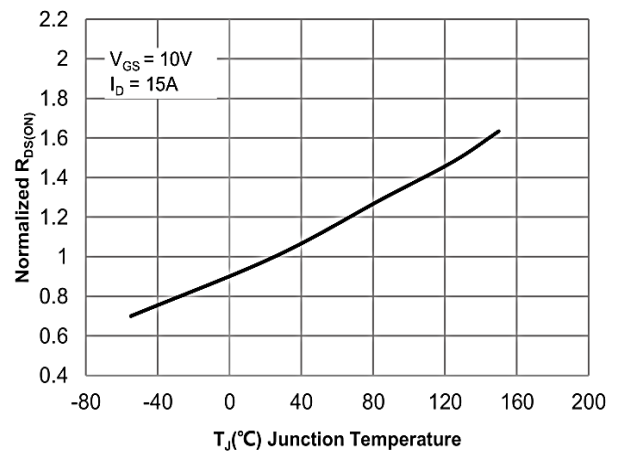


Figure 8: Normalized on Resistance vs. Junction Temperature

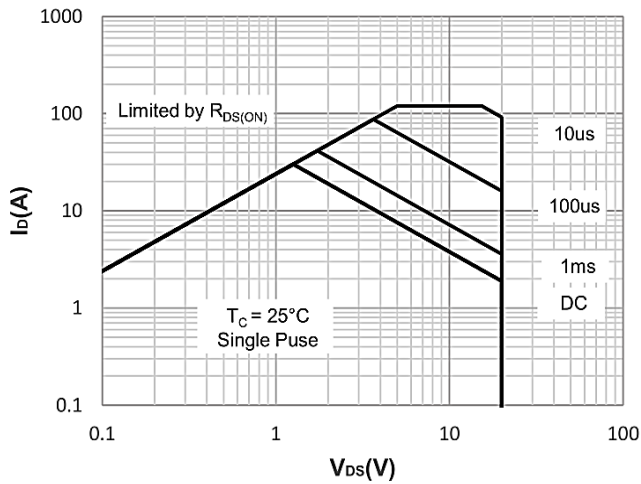


Figure 9: Maximum Safe Operating Area

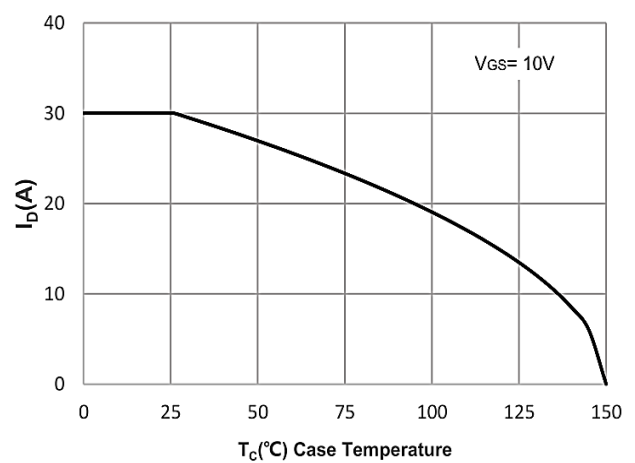


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

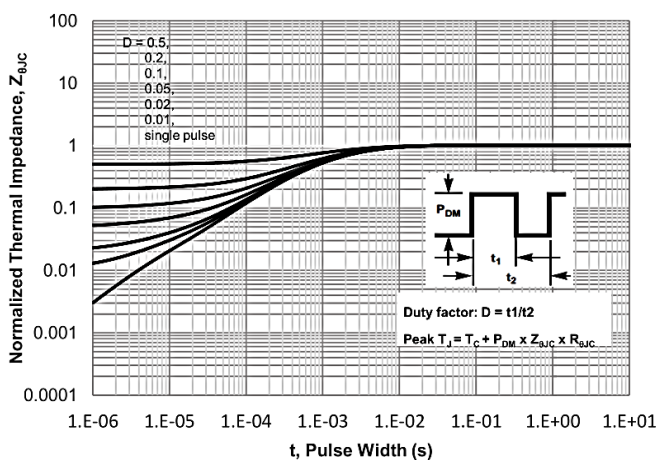


Figure 11: Normalized Maximum Transient Thermal Impedance

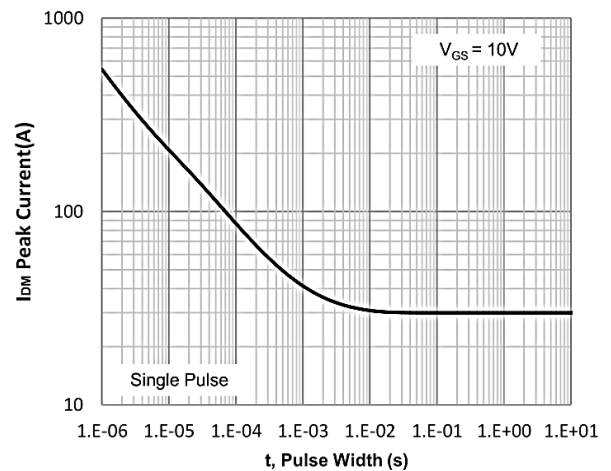
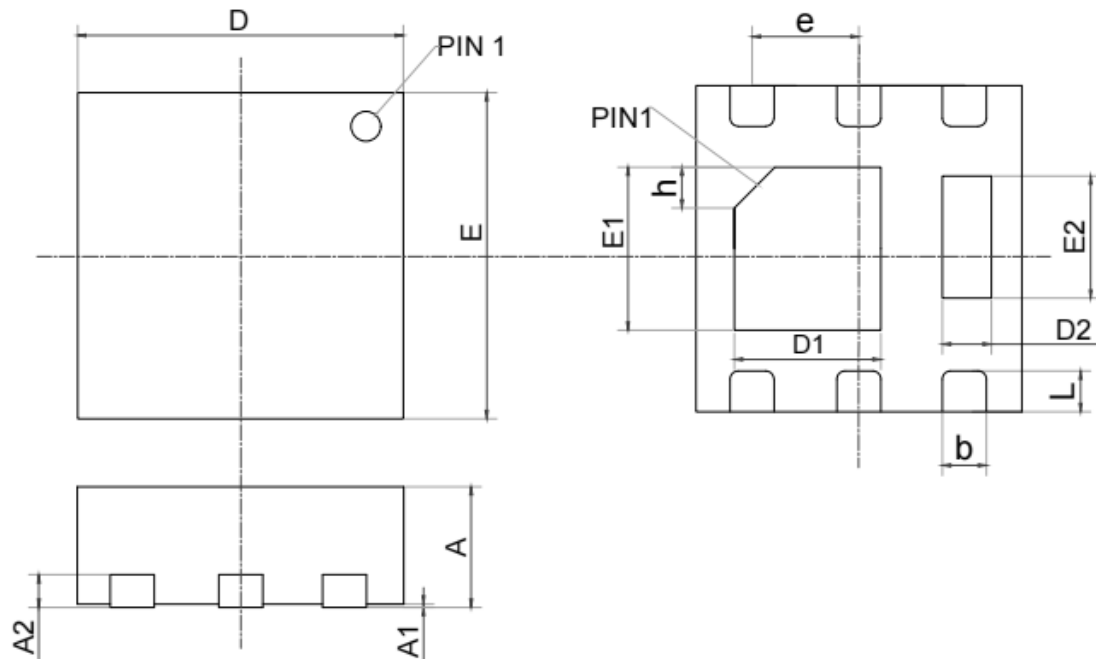


Figure 12: Peak Current Capacity

Package Mechanical Data: QFN2*2-6L



Symbol	Common		
	Min	Nom	Max
A	0.70	0.75	0.80
A1	--	0.02	0.05
A2	0.18	0.20	0.25
b	0.20	0.27	0.34
D	1.95	2.00	2.05
E	1.95	2.00	2.05
D1	0.80	0.90	1.00
E1	0.90	1.00	1.10
D2	0.20	0.30	0.40
E2	0.65	0.75	0.85
L	0.20	0.25	0.35
h	0.20	0.25	0.30
e	0.65 BSC		

20V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
REV1.0	2023/1/31	Initial release

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